

Verizon NEBSTM Compliance: Field Use Optical Connector Polishing Machine

Verizon Technical Purchasing Requirements VZ.TPR.9449 Issue 1, August 2007



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CHANGE CONTROL RECORD:

Version	Date	Action*	Reason for Revision	
1	8/22/2007	New	New document.	
* New, Add, Delete, Change, Reissue				

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1.0 <u>PURPOSE</u>

The purpose of this Verizon Technical Purchasing Requirement document is to provide FOC testing requirements for Field Use Optical Connector Polishing Machines.

2.0 <u>SCOPE</u>

FOC Products

3.0 <u>REFERENCES</u>

GR-326-CORE, Issue 3,	Generic Requirements for Single mode Optical Connectors and
September 1999	Jumper Assemblies
GR-765-CORE Issue 1,	Generic Requirements for Single Fiber Single-Mode Optical Splices
September 1995	and Splicing Systems
GR-1089-CORE, Issue	Electromagnetic Compatibility and Electrical Safety – Generic
4 June 2006	Criteria for Network Telecommunications Equipment

4.0 <u>ACRONYMS</u>

Α	After
APC	Angled Polished Connector
В	Before
D	During
DUT	Device Under Test
FOC	Fiber Optic Components
IL	Insertion Loss
ITL	Independent Testing Laboratory
OM	Optical Measurements
RL	Return Loss
UPC	Ultra Polished Connector



5.0 <u>TEST REQUIREMENTS FOR FIELD USE OPTICAL CONNECTOR</u> <u>POLISHING MACHINES</u>

Verizon is considering using Field Use Optical Connector Polishing Machine for all applications as required. The following are the test requirements for qualifying a Field Use Optical Connector Polishing Machine. All the testing must be completed by a Verizon approved ITL.

FOC -Field Use Optical Connector Polishing Machine Test Plan				
Task Name	Sample Size	OM	Test Description	
Field Use Optical Connector Polishing Machine Qualification				
Connector Optical Requirements	ALL		Initial Loss and Reflectance	
Endface Geometry Requirements (measured per GR-326)	ALL		Protrusion / Undercut, Co-planarity, Endface Angle	
General Requirements and Objectives				
GR-765 3.1: Documentation				
3.1.1: Practices				
3.1.2: WIP				
3.1.3: Safety			Non-toxic	
3.1.5: Preparation			Provide min. length of cable required to rework connector	
GR-765 3.2 General Criteria				
3.2: Dimensions				
(a) Rework Dimensions			Dimensional Requirements for rework product (should be comparable to the applicable Focus document)	
3.2.2: Compatible with Optical Connectors			What manufacturers products are compatible with this polisher	
3.2.3: Index Matching Gel			Should not be required	
3.2.4: Strain Relief			The splicer should provide some means of strain relief when polishing the product	
3.2.5: Fiber Damage			The splicing system should not damage the fibers during the polishing process	
3.2.6: Universal installation			The polisher should work in all installation environments	



FOC -Field Use Optical Connector Polishing Machine Test Plan				
Task Name	Sample Size	OM	Test Description	
Adaptable Clamps and			Should be adaptable to optimize	
Guards			polishing	
GR-765 3.3 Marking, Packaging and				
Shipping				
3.3.1: Marking				
3.3.2: Package Label				
3.3.3: Packaging and Shipping				
3.4: Quality (Not from GR-765)			TL 9000	
Features, Functions, Performance				
Criteria				
GR-765 4.1 Equipment: General				
Requirements and Objectives				
4.1.1: Portability				
4.1.2: Carrying Case				
4.1.3: Surface Finish and			Chemical Resistance	
Markings				
4.1.4: Display and Controls				
4.1.4.1: General display criteria				
4.1.4.2: State of charge Indicator				
4.1.4.3: General Control Criteria				
4.1.6 Features				
4.1.6.1: Support Equipment				
4.1.6.4: Settings and				
Adjustments				
4.1.7: Product Information				
4.1.7 (a): Instructions and Procedures			Equipment should include IS sheets, Operational Instructions and polishing procedures.	
4.1.7 (b): Tools, Materials			List of replacement parts, tools,	
and Supplies			materials and supplies should be provided with the system	
Optical Performance Criteria				
GR-326 4.2.1 Optical Performance Criteria			Loss and Reflectance	
GR-765 4.2.2 Optical Polish Yield (1st Time)			Specify 1st time % Yield, based on Loss/RL/EFG requirements	



FOC -Field Use Optical Connector Polishing Machine Test Plan				
Task Name	Sample Size	OM	Test Description	
Mechanical and Storage Environments Criteria *				
GR-765 4.4 Equipment: Mechanical and Storage Environments Criteria				
4.4.1: Initial Operation			Polisher should function properly as received and be capable of polishing product that meets the requirements specified in sect. 4.21. And 4.2.2	
4.4.3: Shock				
(a): Edgewise Drop and Cornerwise Drop	3A	IL/RL/%Yield I/A	3 in. drop, each corner and edge	
(b): Bottom Surface Drop	3A	IL/RL/%Yield I/A	30 in. Drop on bottom surface of the Polisher	
4.4.4: Vibration, Transportation	3A	IL/RL/%Yield I/A	1 sweep; 1.5G, 10HZ to 500HZ, 0.1 Octave/minute, 3 principle axes	
4.4.5: Storage Environment	3A	IL/RL/%Yield I/A	-40° C, UC/RH, 24 Hrs; 60° C, 95% RH, 24 Hrs	
GR-765 4.5 Equipment: Electrical Requirements				
4.5.1: AC Powered Equipment				
4.5.2: Battery unit				
4.5.3: Battery Operation				
4.5.3.1: Battery Lifetime			Define Battery lifetime in terms of polishing cycles (Room temp and 0° C)	
4.5.3.2: Time-out Interlock				
4.5.3.3: State of Battery Charge				
4.5.4: Electromagnetic Compatibility				
(a) Electromagnetic Interference			Section 3 or GR-1089	
(b) Electrostatic Discharge			Section 2 or GR-1089	
(c) Lightning Surges			Section 4.5.9 or GR-1089	
(d) Electric Safety			Section 7 or GR-1089	
4.6: Material and Consumables Criteria				
4.6.2 Toxicity				
4.6.3 Fungus Resistance				
4.6.4 Shelf Life				
4.6.5 Index Matching Material			"Should not be Required"	
Environmental Performance (Polisher) *				



FOC -Field Use Optical Connector Polishing Machine Test Plan					
Task Name	`ask Name Sample Size OM Test Description				
GR-765 4.7: Polishing - Installation Conditions					
4.7.1: Low Temperature Installation	1A	IL/RL/%Yield I/A	-18° C, UC/RH, Must meet Section 4.2 Req for loss/RL/Yield		
4.7.2: High Temp & High Humidity Installation					
High Temp & Humidity	1A	IL/RL/%Yield I/A	38° C to 90% RH, Must meet Section 4.2 Req for loss/RL/Yield		
Condensing	1A	IL/RL/%Yield I/A	35° C to 100 %RH, Must meet Section 4.2 Req for loss/RL/Yield		
4.7.3: High Temp, Low Humidity Installation	1A	IL/RL/%Yield I/A	50° C to 15% RH, Must meet Section 4.2 Req for loss/RL/Yield		
4.7.4: High Altitude	1A	IL/RL/%Yield I/A	12,000 ft., Must meet Section 4.2 Req for loss/RL/Yield		
4.7.6: Vibration During Operation	1A	IL/RL/%Yield I/A	Amplitude of +/-0.003 in., 10 Hz to 55 Hz to 10 Hz, 1-minute sweep, sweeping until polishing has completed.		
Environmental Life Testing (Finished Product) **					
New product measurements	2A	IL/RL Initial			
End Face Geometry per GR-326	2A	EFG Initial per GR-326			
GR-326 4.4.2.4: Humidity/Condensation Cycle	2A	IL/RL B/D/A	-10° C to 65°C, Hum @ heat, 7 days		
GR-326 4.4.3.1: Vibration Test (3 axis)	2A	IL/RL B/A	10-55 Hz, 2 hours, 1 minute sinusoidal		
GR-326 4.4.3.2: Flex Test	2A	IL/RL B/A	+/- 90 deg, 100 cycles		
GR-326 4.4.3.3: Twist Test	2A	IL/RL B/A	+/- 90 deg, 10 cycles, per specified weight		
GR-326 4.4.3.4: Proof Test	2A	IL/RL B/A	Straight pull and side pull per procedure		
GR-326 4.4.3.5: Trans/w applied load	2A	IL/RL B/D/A	Per procedure		
GR-326 4.4.3.7: Impact Test	2A	IL/RL B/A	Per procedure		
GR-326 4.4.3.8: Durability Test	2A	IL/RL B/D/A	Per procedure		
End Face Geometry per GR-326	2A	EFG Final per GR-326			



Terminology

OM - Optical Measurements B - Before D - During A - After IL - Insertion Loss RL - Return Loss

Optical Requirements

Insertion Loss - Max = 0.25dB, Mean = 0.20dB Return Loss - (APC) = 65dB, (UPC) = 55dB Monitoring All Fibers - to be done at 1310nm/1490nm/1550nm/1625nm

Sample Size

1A	1 polishing jig (max samples - 6) polished reworked once	10 Nominal Ferrule length
2A		10 Nominal Ferrule length
3A		10 Nominal Ferrule length

All references are to source documents GR-326 and GR-765.

Notes:

1st Time Yield numbers are to be provided by the manufacture for the time being, Verizon reserves to provide a specific value at a later date.

The minimal acceptable length: defined as the max number or reworks that can be performed on a connector specified by the polisher manufacturer. This may be a physical length specification.

The Environmental Life Testing (Finished Product) is to be performed sequentially on the same group of samples.

All sequences requiring optical measurements will require end face geometry measurements after the polishing process.

* - The intent of this sequence is to determine if physical and environmental conditions will influence the polishing process.

The samples for these tests are to be in cable assembly format for ease in testing. "Only" one end of the assembly is to be subjected to the polishing. Each DUT will be subject to some form of endface damage, which will be verified before proceeding with the polishing.



Damage to the connector endfaces can be induced using a fine grit polishing paper (TBD) that will at a minimum induce surface defects that will require the repolishing of the enface of the connector.

- ** The objective of this test is to verify the results of the polishing process by evaluating the final product.
 - The samples will be in the form of pigtails and will be tested to a reduced set of requirements specified above with the intent of verifying there are no measurable losses induced by the rework process.